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DATE MAILED: 10/02/2003

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO
09/885,784	06/20/2001	Mong-Song Liang	67,200-327	3661
7590 10/02/2003		EXAMINER		
TUNG & ASSOCIATES			MALDONADO, JULIO J	
Suite 120 838 W. Long Lake Road			ART UNIT PAPER NUMBI	
Bloomfield Ilills, MI 48302			2823	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
Advisory Action	09/885,784	LIANG ET AL.				
	Examin r	Art Unit				
	Julio J. Maldonado	2823				
The MAILING DATE of this communication appe	ars on the cov r sh et with the c	orrespondence address				
THE REPLY FILED 07 September 2003 FAILS TO PLACE THIS APPLICATION IN CONDITION FOR ALLOWANCE. Therefore, further action by the applicant is required to avoid abandonment of this application. A proper reply to a final rejection under 37 CFR 1.113 may only be either: (1) a timely filed amendment which places the application in condition for allowance; (2) a timely filed Notice of Appeal (with appeal fee); or (3) a timely filed Request for Continued Examination (RCE) in compliance with 37 CFR 1.114.						
PERIOD FOR REPLY [check either a) or b)]						
a) The period for reply expires 3 months from the mailing date of b) The period for reply expires on: (1) the mailing date of this Adv event, however, will the statutory period for reply expire later the ONLY CHECK THIS BOX WHEN THE FIRST REPLY WAS 706.07(f).	isory Action, or (2) the date set forth in th an SIX MONTHS from the mailing date of FILED WITHIN TWO MONTHS OF THE	the final rejection. EFINAL REJECTION. See MPEP				
Extensions of time may be obtained under 37 CFR 1.136(a). The dathave been filled is the date for purposes of determining the period of extens 37 CFR 1.17(a) is calculated from: (1) the expiration date of the shortened (b) above, if checked. Any reply received by the Office later than three moleanned patent term adjustment. See 37 CFR 1.704(b).	sion and the corresponding amount of the statutory period for reply originally set in	fee. The appropriate extension fee un the final Office action; or (2) as set for	nder rth in			
1. A Notice of Appeal was filed on Appellant's 37 CFR 1.192(a), or any extension thereof (37 CFR	s Brief must be filed within the p R 1.191(d)), to avoid dismissal o	eriod set forth in of the appeal.				
2. The proposed amendment(s) will not be entered be	ecause:					
(a) I they raise new issues that would require further	er consideration and/or search (see NOTE below);				
(b) they raise the issue of new matter (see Note below);						
(c) they are not deemed to place the application i issues for appeal; and/or	n better form for appeal by mat	erially reducing or simplifying	, the			
(d) they present additional claims without cancel NOTE:	ing a corresponding number of	finally rejected claims.				
3. Applicant's reply has overcome the following reject	tion(s):					
4. Newly proposed or amended claim(s) would canceling the non-allowable claim(s).	be allowable if submitted in a s	eparate, timely filed amendm	nent			
5. ☑ The a) ☐ affidavit, b) ☐ exhibit, or c) ☑ request for application in condition for allowance because: See		idered but does NOT place t	he			
6. The affidavit or exhibit will NOT be considered becaraised by the Examiner in the final rejection.	cause it is not directed SOLELY	to issues which were newly				
7. For purposes of Appeal, the proposed amendment explanation of how the new or amended claims we						
The status of the claim(s) is (or will be) as follows:						
Claim(s) allowed:						
Claim(s) objected to:						
Claim(s) rejected: <u>12,13,16 and 28</u> .						
Claim(s) withdrawn from consideration:						
8. The proposed drawing correction filed on is	a) approved or b) disapp	proved by the Examiner.				
9. Note the attached Information Disclosure Statemen		. 1 ()				
10. Other:		George Flourson Primary Examiner				

Continuation of 5, does NOT place the application in condition for allowance because: Applicant's arguments filed 09/09/2003 have been fully considered but they are not persuasive.

Applicant argues, "... applicant asserts that Mountain neither explicitly nor implicitly discloses removing a second substrate from a laminated completely fabricated semiconductor integrated circuit microelectronic fabrication while employing a dielectric isolated metallization pattern as a stop layer. Applicant further notes that the Examiner does not apparently assert that Mountain explicitly discloses the same...Thus, Mountain implicitly would have no motivation to employ a dielectric isolated metallization pattern for etch stop purposes, but rather an etch stop layer formed of a single etch stop material appears entirely adequate within Mountain's invention...". In response to these arguments, applicant asserts that Mountain does not expressly teach a laminated completely fabricated semiconductor integrated circuit microelectronic fabrication as claimed. However, Mountain wasn't relied upon that purpose. Mountain was relied on removing substrates and using a dielectric layer as an etch stop layer during such removing step. Furthermore, by including the etch stop layer and the removing steps of Mountain into the laminated completely fabricated semiconductor integrated circuit microelectronic fabrication as taught by Kelly et al., the step of "removing a second substrate from a laminated completely fabricated semiconductor integrated circuit microelectronic fabrication while employing a dielectric isolated metallization pattern as a stop layer" as recited in claim 16 would be achieved.

Also, applicant argues, "...Haq does not apparently require a dielectric isolated metallization pattern by formed upon Haq's substrate prior to thinning thereof, nor does Haq disclose employing the dielectric isolated metallization pattern as a stop layer when thinning Haq's substrate... Haq's invention is preferably employed with the context of a semiconductor substrate having defined on the front side thereo live circuits...Haq's invention is rendered inoperative for its intended purpose since such complete thinning and removal of Haq's semiconductor substrate would also remove Haq's semiconductor devices and render inoperative Haq's live circuits...". In response to this argument, Haq was relied on the teaching of thinning substrates by using CMP processes. Furthermore, Haq teaches that the process may be used on various types of substrate, including live substrates (Haq, column 3, lines 18 - 25)...